Lecture 26: 12/04/03 A.R. Neureuther

Version Date 11/30/03

Review for the Final Exam

Likely 7 Problems

* Possible Bonus = 2/3 best +1/3 worst

Midterm Bonus = 2/3 best +1/3 worst

Transients*

Logic Functions and Timing Diagrams

Circuit Analysis with dependent Sources

Op-Amps*

Load Line and Static Analysis of Logic Gates

CMOS Logic Functions, Delay, Latches

Diode Circuit Analysis, Voltage Controlled R

See Web Site under Exams for Coverage, Review Sessions and Office Hours

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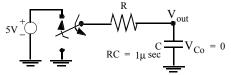
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Lecture 26: 12/04/03 A.R. Neureuther

Lecture 7

PULSE: Output is Rising exponential exponential

Example: Switch rises at t =0, falls at t = 0.1, 1 or 10µsec (Do 1µsec case)



Now starting at 1μsec we are discharging the capacitor so the form is a falling exponential with initial value 3.16 V:

Solution: for RC = 1μ sec: during the first rise V obeys:

$$V = 5[1 - e^{\frac{-t}{10^{-6}}}]$$

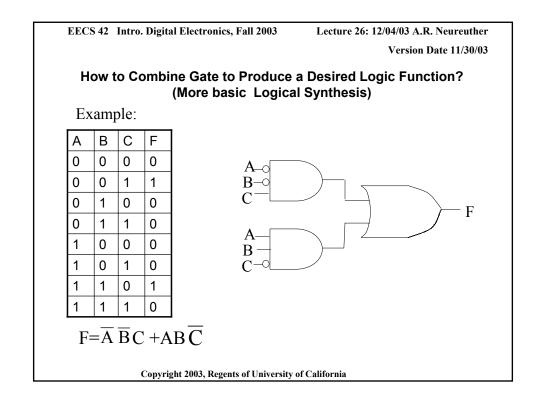
What is equation?

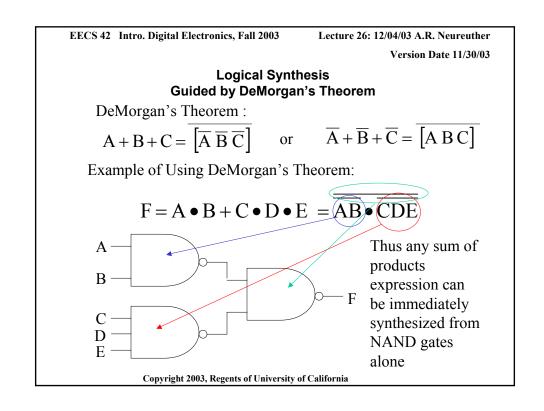
What is equation?

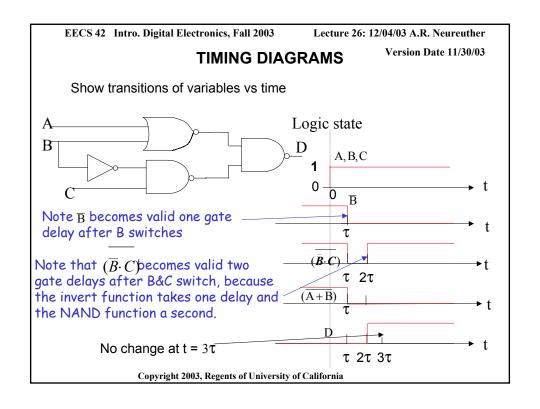
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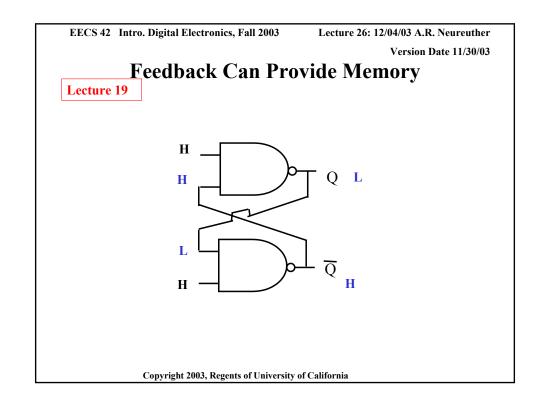
Thus at $t = 1\mu sec$, rising voltage reaches

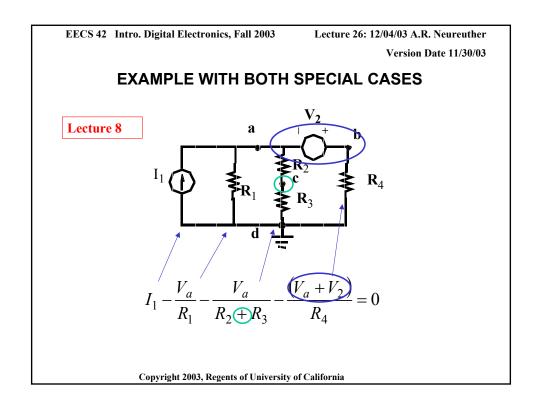
$$5[1-e^{-1}] = 3.16V$$

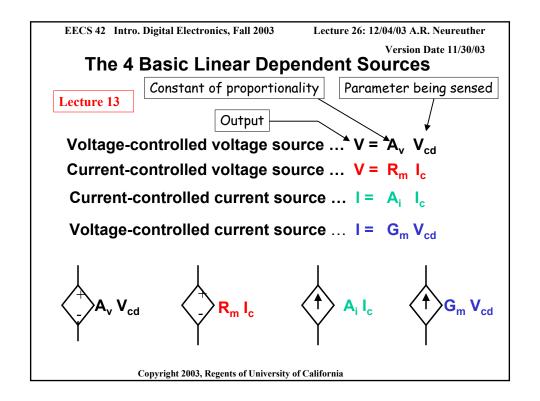


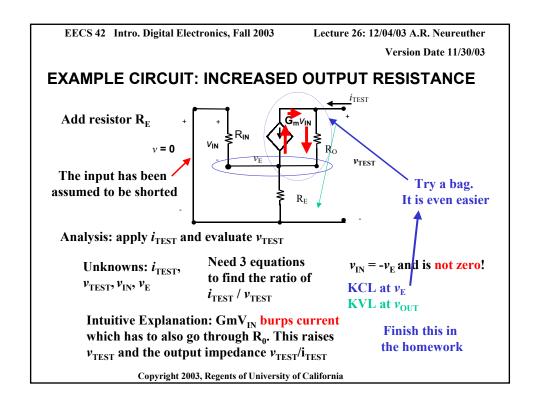


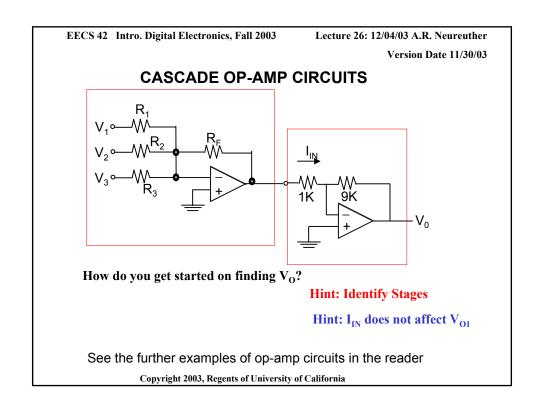




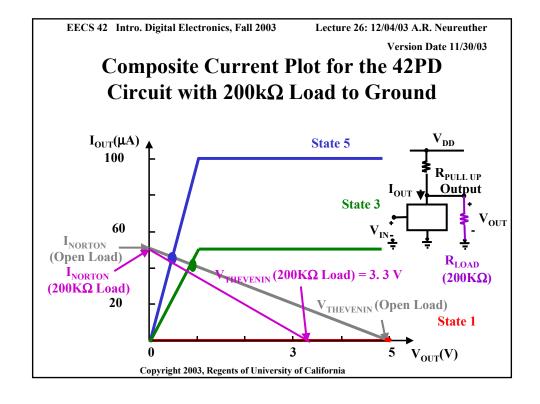


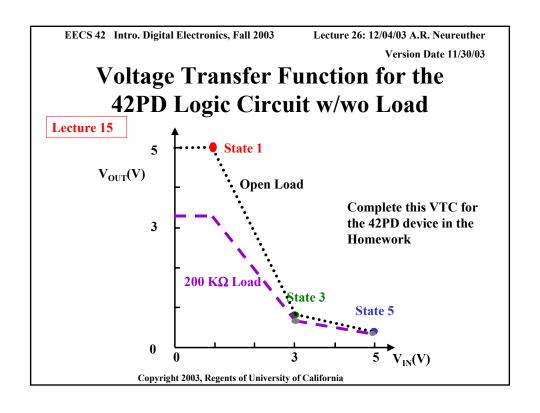


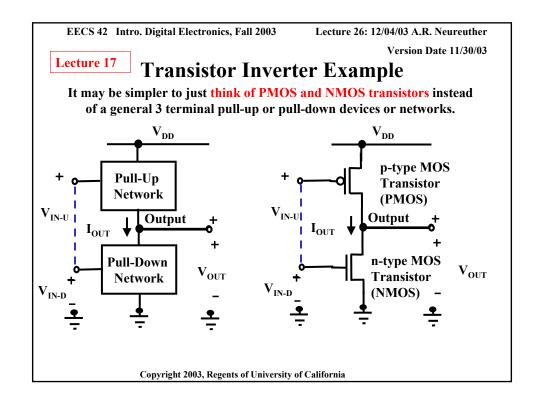


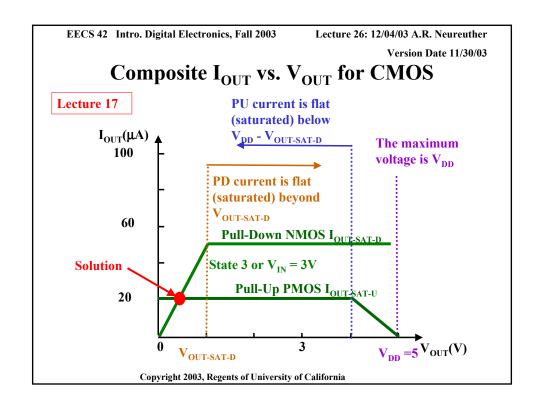


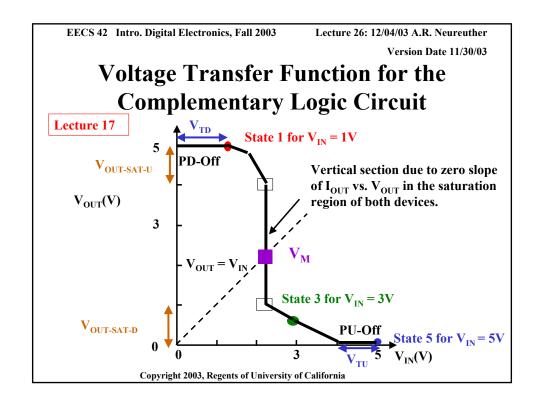
EECS 42 Intro. Digital Electronics, Fall 2003 Lecture 26: 12/04/03 A.R. Neureuther Version Date 11/30/03 Lecture 17 Saturation Current NMOS Model Current I_{OUT} only flows when V_{IN} is larger than the threshold value V_{TD} and the current is proportional to V_{OUT} up to $V_{OUT\text{-SAT-D}}$ where it reaches the saturation current $I_{OUT-SAT-D} = k_D (V_{IN} - V_{TD}) V_{OUT-SAT-D}$ Note that we have added an extra parameter to distinguish between threshold ($V_{TD}\!)$ and saturation ($V_{OUT\text{-}SAT\text{-}D}\!)$. 100 **†**I_{OUT}(µA) Example: Use these $k_D=25~\mu A/V^2$ State 3 $V_{IN} = 3V$ $V_{TD} = 1V$ values in the Saturation (with V_{OUT}) homework. $V_{OUT-SAT-D} = 1V$ 60 Linear (with V_{OUT}) $I_{OUT-SAT-PD} = 25 \frac{\mu A}{V^2} (3V - 1V) 1V = 50 \mu A$ 20 Copyright 2003, Regents of University of California











 $\frac{3}{4}$ V_{DD} is the average value of V_{OUT}

Approximate the NMOS device curve by a straight line from (0,0) to ($I_{OUT\text{-}SAT\text{-}D}, {}^3\!\!/_4 \, V_{DD}$).

Interpret the straight line as a resistor with

slope =
$$1/R = \frac{3}{4} V_{DD}/I_{SAT}$$

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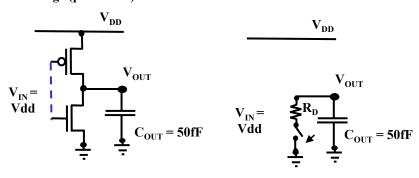
Lecture 26: 12/04/03 A.R. Neureuther

Version Date 11/30/03

Lecture 18

Inverter Propagation Delay

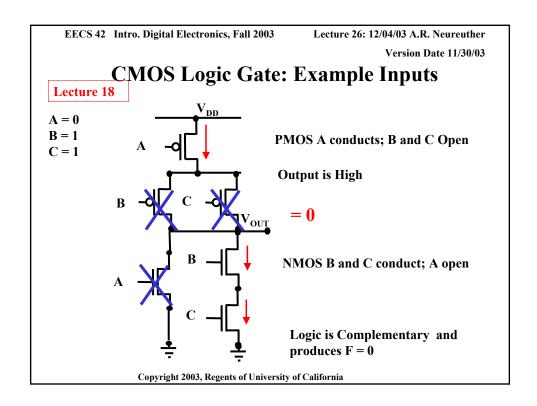
Discharge (pull-down)

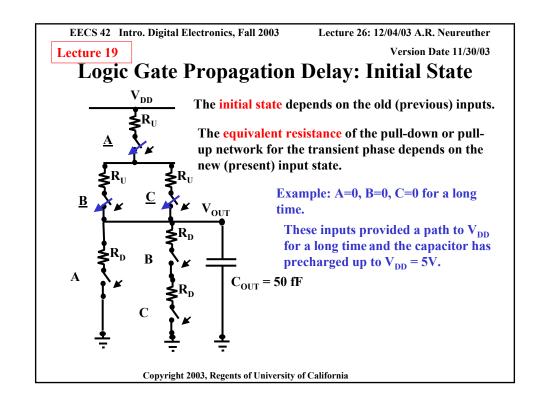


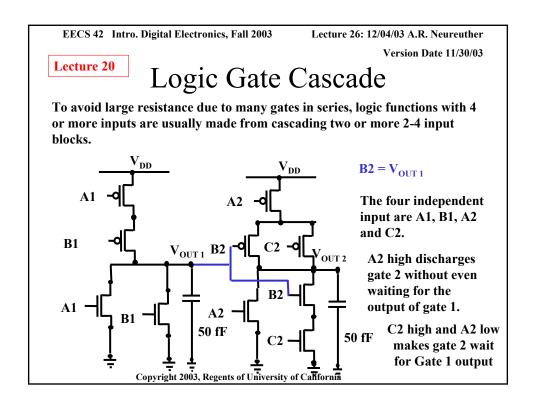
 $\Delta t = 0.69 R_D C_{OUT} = 0.69 (10 k\Omega) (50 fF) = 345 ps$

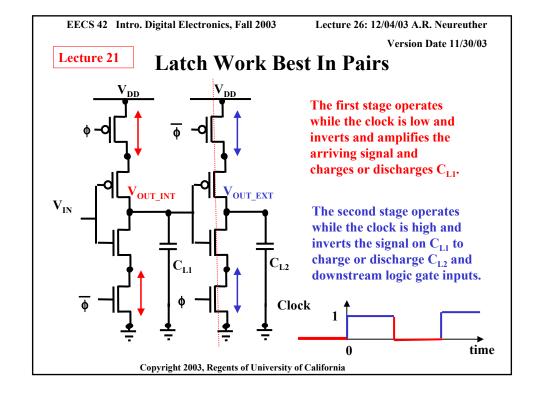
Discharge (pull-up)

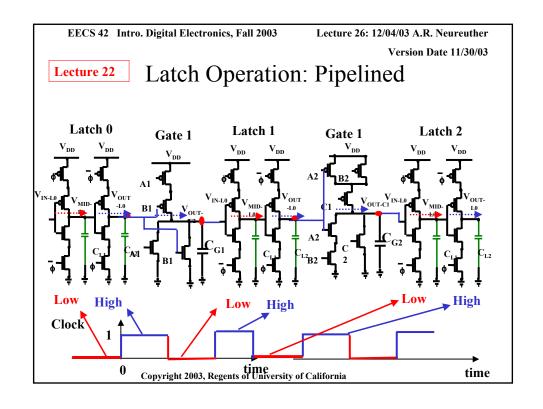
$$\Delta t = 0.69 R_U C_{OUT} = 0.69 (10 k\Omega) (50 fF) = 345 ps$$

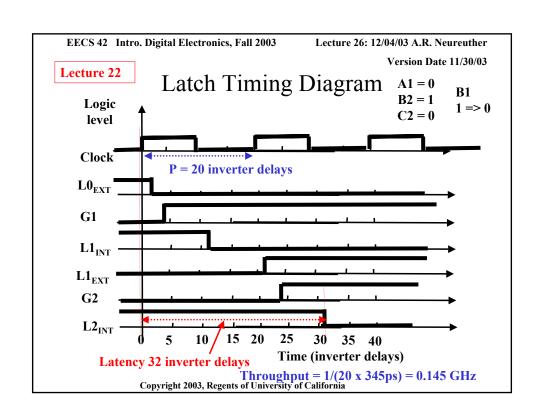












EECS 42 Intro. Digital Electronics, Fall 2003

Lecture 26: 12/04/03 A.R. Neureuther

Version Date 11/30/03

Lecture 22

Latency and Throughput

Latency L is the delay between the rising edge of the clock on L0 and the data being valid internally in the last latch.

$$\begin{split} L_{LUMPED} &= \tau_{L_EXT} + \tau_{GATE1} + \tau_{GATE2} + \tau_{L_INT} \\ &= 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} = 8\tau_{INV} \end{split}$$

$$\begin{split} L_{PIPLINED} &= \tau_{L_EXT} + \tau_{GATE1} + \tau_{L_INT} + \tau_{L_EXT} + \tau_{GATE2} + \tau_{L_INT} \\ &= 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} = 12\tau_{INV} \end{split}$$

Throughput T is the bits per second through the latches and is the maximum clock frequency.

$$\begin{aligned} \mathbf{P}_{\text{LUMPED}} &= \mathbf{\tau}_{\text{L_EXT}} + \mathbf{\tau}_{\text{GATE1}} + \mathbf{\tau}_{\text{GATE2}} + \mathbf{\tau}_{\text{L_INT}} \\ &= 2\mathbf{\tau}_{\text{INV}} + 2\mathbf{\tau}_{\text{INV}} + 2\mathbf{\tau}_{\text{INV}} + 2\mathbf{\tau}_{\text{INV}} = 8\mathbf{\tau}_{\text{INV}} \end{aligned}$$

$$F_{LUMPED} = 1/8(345ps) = 0.36 \text{ GHz}$$

$$\begin{split} P_{PIPELINED} &= \tau_{L_EXT} + MAX(\tau_{GATE1}, \tau_{GATE2}) + \tau_{L_INT} \\ &= 2\tau_{INV} + 2\tau_{INV} + 2\tau_{INV} = 6\tau_{INV} \quad F_{PIPLINED} = 1/6(345ps) = 0.48 \text{ GHz} \end{split}$$

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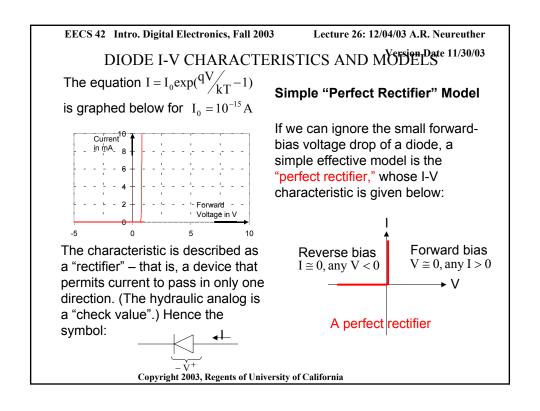
Lecture 26: 12/04/03 A.R. Neureuther

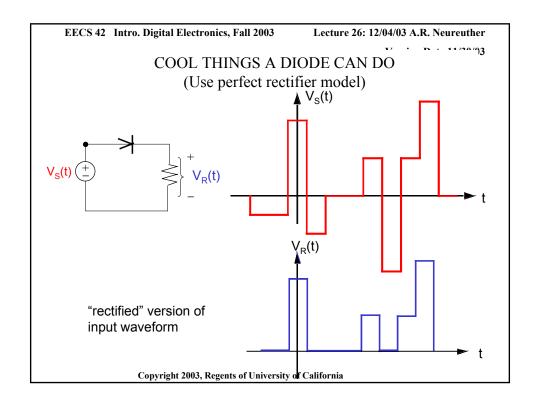
Lecture 25: on blackboard

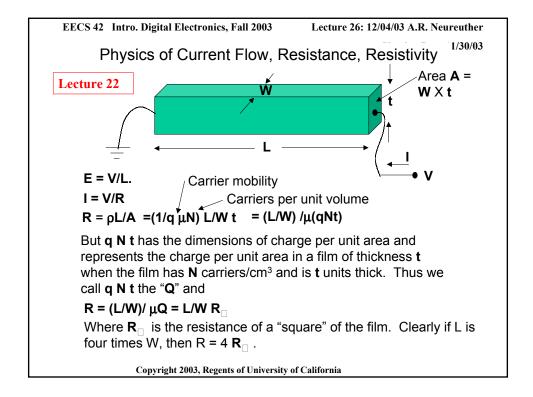
Version Date 11/30/03

Limitations of Power Consumption

- The resistive load of NMOS results in D.C. current and hence static power consumption given by the product of current times voltage.
- CMOS avoids this static loss as the pull-up device shuts off the current completely.
- CMOS still suffers a.c. power consumption that is proportional to the switching frequency.
- $\, \cdot \,$ The energy expended per cycle of in charging and discharging can never be less than CV^2







EECS 42 Intro. Digital Electronics, Fall 2003

Relation of Current to Physical Parameters $I_D = \mu_n C_{ox} \left(\frac{W}{L}\right)_n (V_{GS} - V_T) \cdot V_{OUT-SAT-n}$ Mobility of carriers

Oxide thickness

Oxide thickness $\mu_n = 500 \left(cm^2 / V_S\right)$ $\mu_p = 150 \left(cm^2 / V_S\right)$ $C_{ox} = \frac{\varepsilon_{ox}}{t_{ox}} = \frac{\left(8.85x10^{-14} F / cm\right)(3.9)}{6x10^{-7} cm} = 5.75x10^{-7} F / cm^2$ $V_{OUT-SAT-n} = E_{Crit} \cdot L = 10^4 \left(V / cm\right) \cdot 0.25x10^{-4} cm = 0.25V$